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1	BRS	L1	18	(fail adj bit with (compress\$3 or encod\$3 or cod\$3))	USPAT	2004/05/13 22:03
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3	BRS	L3	3	2 and (fail with (shape or bound\$5 or contour))	USPAT	2004/05/13 22:05
4	BRS	L4	0	2 and (fail with (shape or bound\$5 or contour) same (ratio or rate))	USPAT	2004/05/13 22:06
5	BRS	L5	79	(fail or defect\$5) adj bit with (compress\$3 or encod\$3 or cod\$3)	USPAT	2004/05/13 22:06
6	BRS	L6	28	5 and ((fail or defect\$5) with (area or map))	USPAT	2004/05/13 22:07
7	BRS	L7	4	6 and ((fail or defect\$5) with (shape or bound\$5 or contour))	USPAT	2004/05/13 22:07
8	BRS	L8	0	7 and ((fail or defect\$5) with (shape or bound\$5 or contour) same (ratio or rate))	USPAT	2004/05/13 22:06
9	BRS	L9	47	(fail or defect\$5) adj bit with (compress\$3 or encod\$3 or cod\$3)	EPO; JPO; DERWEN T; IBM_TD B	2004/05/13 22:06
10	BRS	L10	13	9 and ((fail or defect\$5) with (area or map))	EPO; JPO; DERWEN T; IBM_TD B	2004/05/13 22:07
11	BRS	L11	1	10 and ((fail or defect\$5) with (shape or bound\$5 or contour))	US-PGP UB; EPO; JPO; DERWEN T; IBM_TD B	2004/05/13 22:08

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